

**Search Notes**

Application/Control No.

10/066,060

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

TEIG ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	13,14,9,10 .4	10/19/2004	PK
Above	updated	5/31/2005	PK
Above	updated	12/7/2005	PK
Above	new	12/7/2005	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) -USPAT, USPGPUB Class/Sub searched: 716/1-18 (see attached)	10/19/2004	PK
-EPO, JPO, IBM TDB, Derwent (see attached)	10/19/2004	PK
IEEE/IEEE Xplore (see attached)	10/19/2004	PK
Above updated search	5/31/2005	PK
Above updated and new search (see attached)	12/7/2005	PK